#### [CLAIMS]

#### [Claim 1]

A quantum dot light-emitting diode comprising a pair of top and bottom electrodes and a quantum dot light-emitting layer provided between the electrodes wherein an inorganic electron transport layer is formed between the quantum dot light-emitting layer and the top electrode.

# [Claim 2]

The quantum dot light-emitting diode according to claim 1, wherein the diode comprises an anode, a hole transport layer, a quantum dot light-emitting layer, an inorganic electron transport layer and a cathode formed in this order on a substrate.

## [Claim 3]

The quantum dot light-emitting diode according to claim 1 or 2, wherein the inorganic electron transport layer is made of an oxide selected from the group consisting of TiO<sub>2</sub>, ZnO, SiO<sub>2</sub>, SnO<sub>2</sub>, WO<sub>3</sub>, Ta<sub>2</sub>O<sub>3</sub>, BaTiO<sub>3</sub>, BaZrO<sub>3</sub>, ZrO<sub>2</sub>, HfO<sub>2</sub>, Al<sub>2</sub>O<sub>3</sub>, Y<sub>2</sub>O<sub>3</sub> and ZrSiO<sub>4</sub>; the nitride Si<sub>3</sub>N<sub>4</sub>; or a semiconductor compound selected from the group consisting of CdS, ZnSe and ZnS.

### [Claim 4]

The quantum dot light-emitting diode according to claim 1 or 2, wherein the quantum dot light-emitting layer is made of a material selected from the group consisting of: Group II-VI compound semiconductor nanocrystals, including CdS, CdSe, CdTe, ZnS, ZnSe, ZnTe, HgS, HgSe and HgTe; Group III-V compound semiconductor nanocrystals, including GaN, GaP, GaAs, InP and InAs; PbS; PbSe; PbTe; CdSe/ZnS; CdS/ZnSe; and InP/ZnS.

### [Claim 5]

The quantum dot light-emitting diode according to claim 1 or 2, wherein the inorganic electron transport layer is formed by a solution coating process selected from the group consisting of solgel coating, spin coating, printing, casting and spraying, or a vapor coating process selected from the group consisting of chemical vapor deposition (CVD), sputtering, e-beam evaporation and vacuum deposition.

# [Claim 6]

The quantum dot light-emitting diode according to claim 2, wherein the hole transport layer is made of a material selected from the group consisting of poly(3,4-ethylenedioxythiophene) (PEDOT)/polystyrene para-sulfonate (PSS) derivatives, poly-N-vinylcarbazole derivatives, polyphenylenevinylene derivatives, polyparaphenylene derivatives, polymethacrylate derivatives, poly(9,9-octylfluorene) derivatives, poly(spiro-fluorene) derivatives, N,N'-diphenyl-N,N'-bis(3-methylphenyl)-(1,1'-biphenyl)-4,4'-diamine (TPD), N,N'-di(naphthalene-1-yl)-N,N'diphenyl-benzidine (NPB), tris(3-methylphenylphenylamino)-triphenylamine (m-MTDATA), and poly(9,9'-dioctylfluorene-co-N-(4-butylphenyl)diphenylamine (TFB).